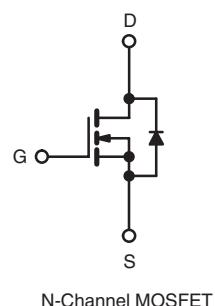
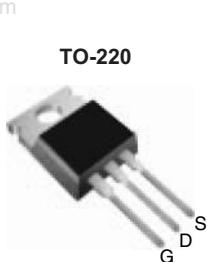


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	600
R _{DS(on)} (Ω)	V _{GS} = 10 V 1.2
Q _g (Max.) (nC)	60
Q _{gs} (nC)	8.3
Q _{gd} (nC)	30
Configuration	Single


RoHS*
COMPLIANT


FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Parallelizing
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION

Package	TO-220
Lead (Pb)-free	IRFBC40PbF SiHFBC40-E3
SnPb	IRFBC40 SiHFBC40

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	600	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I _D
		T _C = 100 °C	3.9
Pulsed Drain Current ^a	I _{DM}	25	A
Linear Derating Factor		1.0	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	570	mJ
Repetitive Avalanche Current ^a	I _{AR}	6.2	A
Repetitive Avalanche Energy ^a	E _{AR}	13	mJ
Maximum Power Dissipation	P _D	125	W
Peak Diode Recovery dV/dt ^c	dV/dt	3.0	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	
Mounting Torque	6-32 or M3 screw	10	lbf · in
		1.1	N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 50 V, starting T_J = 25 °C, L = 27 mH, R_G = 25 Ω, I_{AS} = 6.2 A (see fig. 12).

c. I_{SD} ≤ 6.2 A, dI/dt ≤ 80 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

SPECIFICATIONS $T_J = 25^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	600	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$	-	0.7	-	$^{\circ}\text{C}/\text{V}$	
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	2.0	-	4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600 \text{ V}$, $V_{GS} = 0 \text{ V}$	-	-	100	μA	
		$V_{DS} = 480 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^{\circ}\text{C}$	-	-	500		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 3.7 \text{ A}^b$	-	-	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 100 \text{ V}$	$I_D = 3.7 \text{ A}^b$	4.7	-	-	
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5	-	1300	-	pF	
Output Capacitance	C_{oss}		-	160	-		
Reverse Transfer Capacitance	C_{rss}		-	30	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 6.2 \text{ A}$, $V_{DS} = 360 \text{ V}$, see fig. 6 and 13 ^b	-	-	60	
Gate-Source Charge	Q_{gs}			-	-	8.3	
Gate-Drain Charge	Q_{gd}			-	-	30	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 300 \text{ V}$, $I_D = 6.2 \text{ A}$, $R_G = 9.1 \Omega$, $R_D = 47 \Omega$, see fig. 10 ^b	-	13	-	ns	
Rise Time	t_r		-	18	-		
Turn-Off Delay Time	$t_{d(off)}$		-	55	-		
Fall Time	t_f		-	20	-		
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH
Internal Source Inductance	L_S			-	7.5	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	6.2	A
Pulsed Diode Forward Current ^a	I_{SM}			-	-	25	
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}\text{C}$, $I_S = 6.2 \text{ A}$, $V_{GS} = 0 \text{ V}^b$	-	-	1.5	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^{\circ}\text{C}$, $I_F = 6.2 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$	-	450	940	ns	
Body Diode Reverse Recovery Charge	Q_{rr}		-	3.8	7.9	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

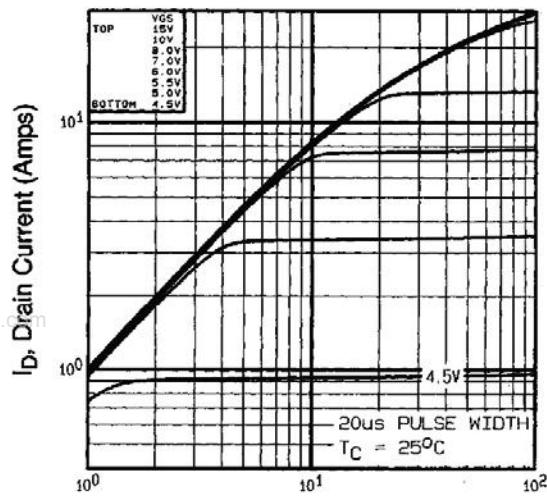
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


Fig. 1 - Typical Output Characteristics, $T_C = 25^\circ\text{C}$

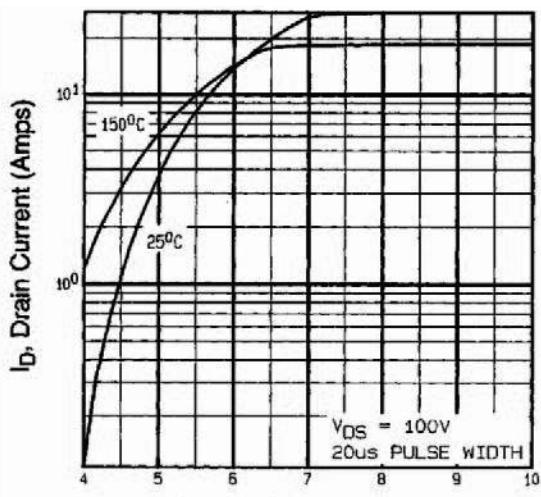


Fig. 3 - Typical Transfer Characteristics

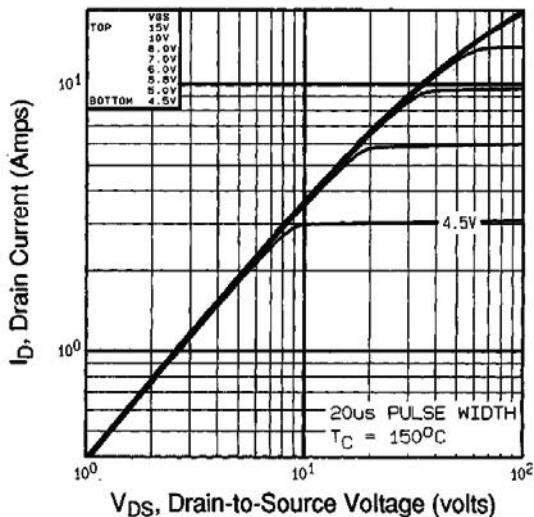


Fig. 2 - Typical Output Characteristics, $T_C = 150^\circ\text{C}$

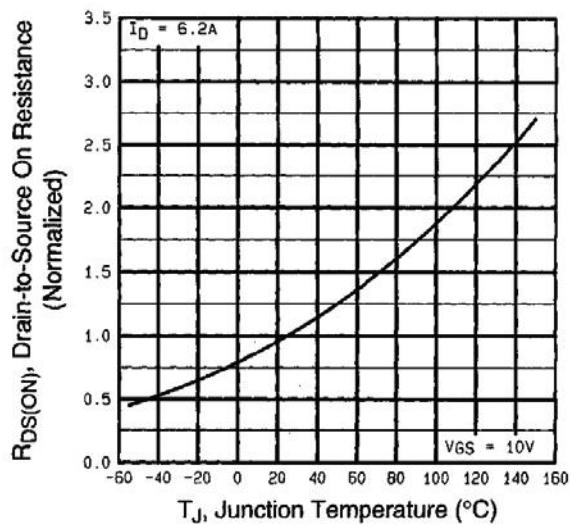


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFBC40, SiHFBC40

Vishay Siliconix

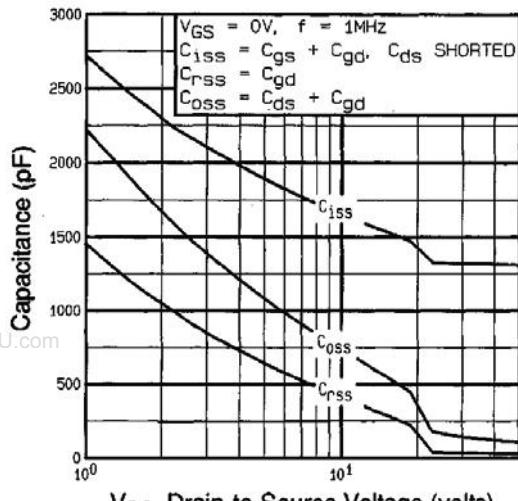


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

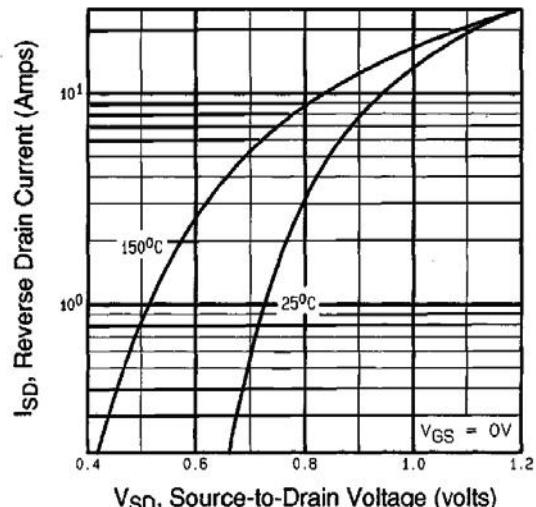


Fig. 7 - Typical Source-Drain Diode Forward Voltage

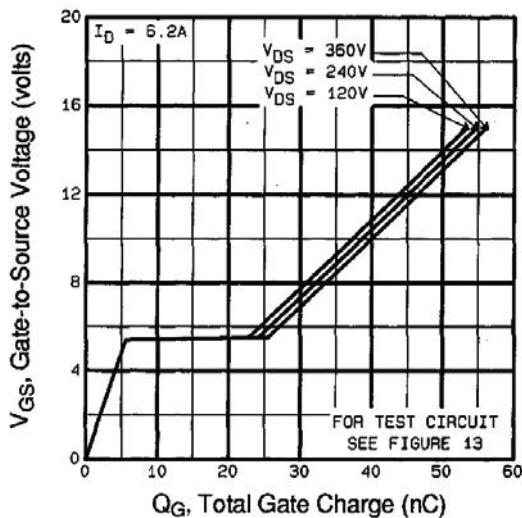


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

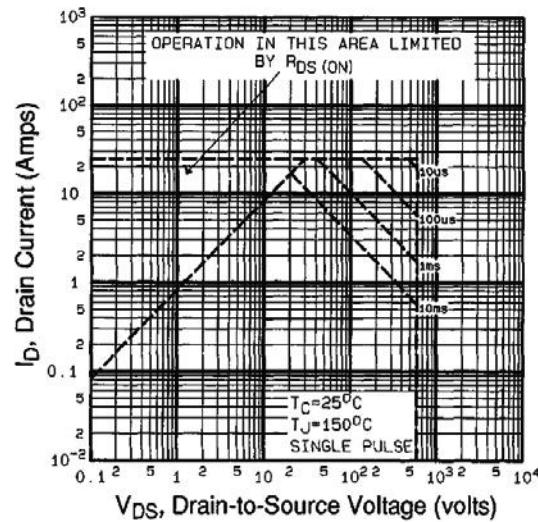


Fig. 8 - Maximum Safe Operating Area

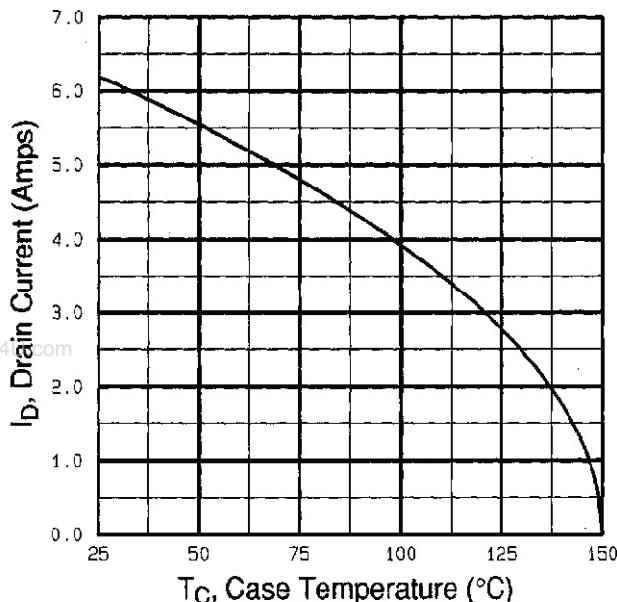


Fig. 9 - Maximum Drain Current vs. Case Temperature

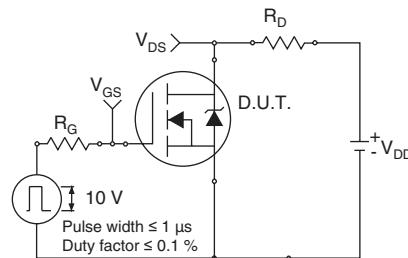


Fig. 10a - Switching Time Test Circuit

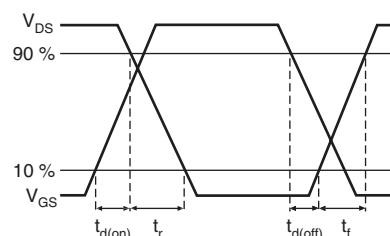


Fig. 10b - Switching Time Waveforms

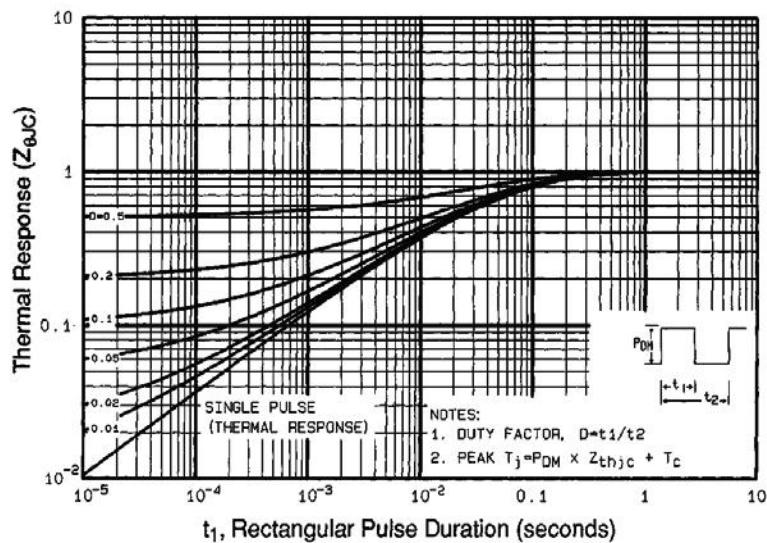


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

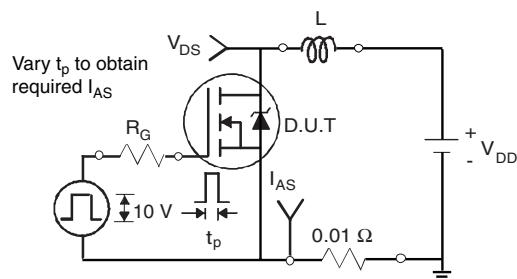


Fig. 12a - Unclamped Inductive Test Circuit

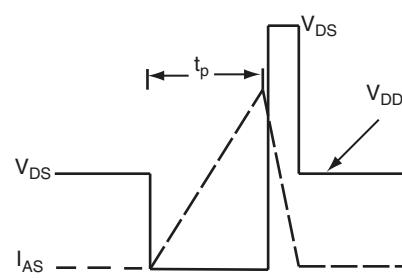


Fig. 12b - Unclamped Inductive Waveforms

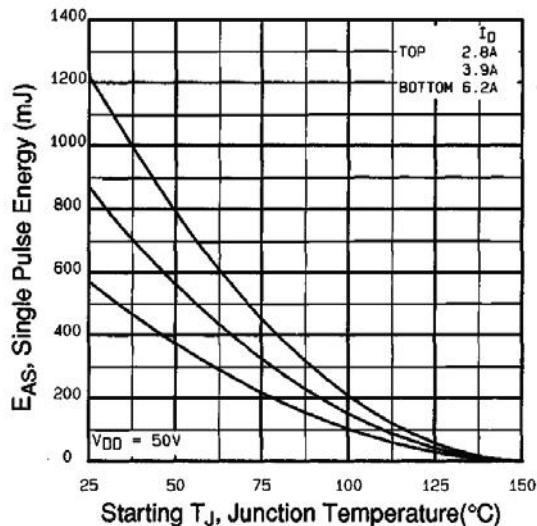


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

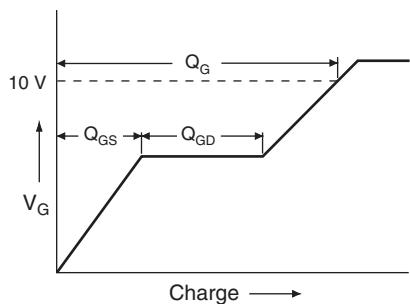


Fig. 13a - Basic Gate Charge Waveform

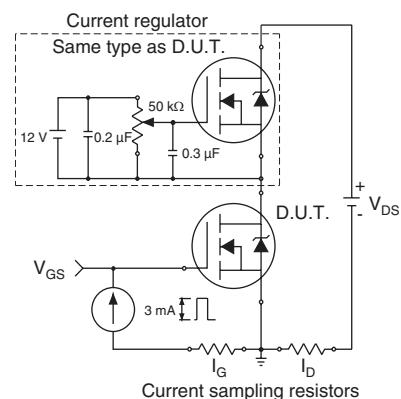
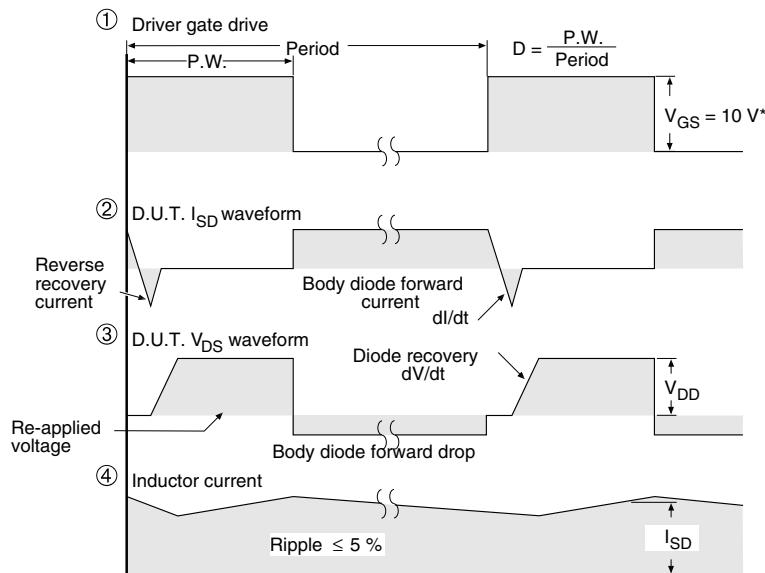
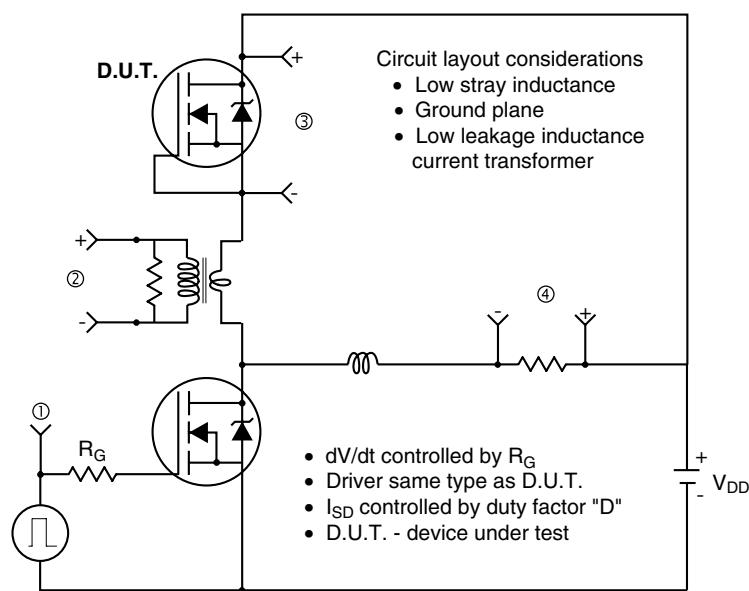


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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